

Search Notes

Application/Control No.

10/815,899

Examiner

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Applicant(s)/Patent under
Reexamination

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Art Unit

2181

SEARCHED

Class	Subclass	Date	Examiner
710	5-7, 54, 310-311	10/23/2006	CS
711	137-151	10/23/2006	CS

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
710	6,54,310		

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
PALM - DOUBLE PATENTING	10/23/2006	CS
EAST (USPGPUB, USPAT, USOCR, DPO, JPO, DERENT , IBMTDB)	10/23/2006	CS